

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Application Number	10/587,303
Confirmation Number	6535
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First Named Inventor	Katsuhiro TAKENAGA
Art Unit	2886
Examiner Name	Tara S PAJOHI
Attorney Docket Number	Q96164

U.S. PATENTS

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U.S. PATENT APPLICATION PUBLICATIONS

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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No	Foreign Document Number ³	Country Code ²	Kind Code ⁴	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁵
	1.	2003-195085	JP	A	2003-07-09	Fitel USA Corp		

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	T ⁵
	1.	Shin-Etsu Quartz Products Co., Ltd., "Quartz Glass Technical Guide - 1 Chemical and Physical Properties of Quartz Glass", p. 7, Tokyo, Japan, October 1, 2005. (available at: http://www.sqp.co.jp/seihin/catalog/pdf/g1.pdf)	
	2.	Shin-Etsu Quartz Products Co., Ltd., "Quartz Glass Technical Guide - 2 Optical Properties of Quartz Glass", p. 7, Tokyo, Japan, October 1, 2005. (available at: http://www.sqp.co.jp/seihin/catalog/pdf/g2.pdf)	
	3.	The Institute of Electrical and Electronics Engineers, Inc. (IEEE), "802.3ae: IEEE Standard for Information Technology - Telecommunications and information exchange between systems - Local and metropolitan area networks - Specific requirements, Part 3", pages 401-443, New York, NY August 30, 2002.	
	4.	International Electrotechnical Commission (IEC), "IEC/PAS 60793-1-49 Edition 1.0, Pre-Standard Optical fibres - Part 1-49: Measurement methods and test procedures - Differential mode delay", Geneva Switzerland, May 2005.	
	5.	International Electrotechnical Commission (IEC), "IEC 60793-2-10 Ed. 2.0: Optical Fibres - Part 2-10: Product specifications - Sectional specification for category A1 multimode fibres", Geneva, Switzerland July 23, 2004	

EXAMINER SIGNATURE

Examiner Signature		Date Considered	
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